



ANSI/EIA-364-48A-2006
Approved: March 22, 2006

EIA STANDARD

TP-48A

METALLIC COATING THICKNESS MEASUREMENT OF CONTACTS TEST PROCEDURE FOR ELECTRICAL CONNECTORS

**This EIA standard has been superseded by the following
ASTM specifications**

Description	EIA-364-48 test method	ASTM equivalent
Microsection – Optical	Method A	ASTM B-487
Microsection – SEM	—	ASTM B-748
Bata backscatter	Method B	ASTM B-567
X-ray fluorescence	Method C	ASTM B-568
Eddy current	Method D	ASTM B-244
Coulometry	Method E	ASTM B-504
Weight gain	Method F	ASTM B-767

EIA/ECA-364-48A

(Revision of EIA-364-48)

MARCH 2000



Electronic Components, Assemblies & Materials Association

**ELECTRONIC COMPONENTS, ASSEMBLIES & MATERIALS
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(From Standards Proposal No. 5071 formulated under the cognizance of the CE-2.0 National Connectors Standards Committee.

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